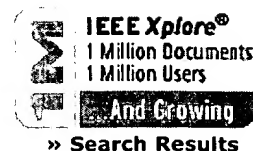


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[\[Abstract\]](#) [\[PDF Full-Text \(600 KB\)\]](#) **IEEE CNF****4 Built-in parametric test for controlled impedance I/Os***Haulin, T.;*

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5 A compact array processor based on self-timed simultaneous bidirectional signalling

Yacoub, G.Y.; Soni, T.; Ku, W.H.;

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7 Signal integrity analysis of high-speed, high-pin-count digital packages

Tsai, C.-T.;

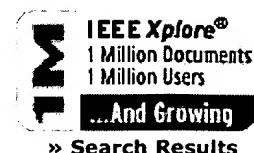
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2 Control and implementation of a three-phase voltage-doubler reversible AC to DC converter*Ching-Tsai Pan; Maoh-Chin Jiang;*

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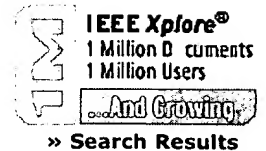
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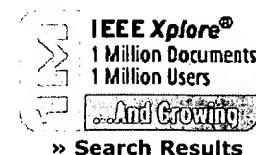
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Tiemeijer, L.F.; Thijs, P.J.A.; Van Dongen, T.; Binsma, J.J.M.; Jansen, E.J.; Kuindersma, P.I.; Cuijpers, G.P.J.M.; Walczyk, S.;
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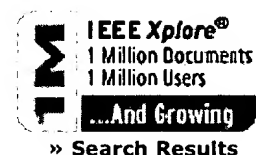
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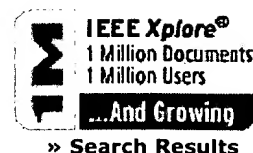
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Thermal and Thermomechanical Phenomena in Electronic Systems, 2002. ITherm 2002. The Eighth Intersociety Conference on , 30 May-1 June 2002

Pages:425 - 432

[\[Abstract\]](#)[\[PDF Full-Text \(756 KB\)\]](#)**IEEE CNF****2 Local convection heat transfer coefficient measurement in a wavy channel with flow disturbers***Dini, S.; Veronesi, R.R.; Huff, R.K.;*

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Security Technology, 2001 IEEE 35th International Carnahan Conference on , 16-19 Oct. 2001

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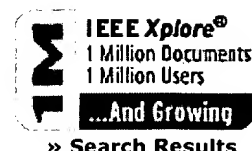
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Mahalingam, L.; Andrews, J.; Drye, J.;

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